



FOR IMMEDIATE RELEASE

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**AEHR TEST SYSTEMS DELIVERS
FOX FULL WAFER TEST & BURN-IN SYSTEM**

Fremont, CA (March 25, 2004) – Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced the delivery of a FOX™ full wafer contact test and burn-in system to Fuji Xerox Co., Ltd. The system will be used to burn-in Vertical Cavity Surface Emitting Laser diodes (VCSELs) produced by Fuji Xerox.

“We are very pleased to have shipped one of our FOX systems for burning-in laser diodes,” said Rhea Posedel, chairman and chief executive officer of Aehr Test Systems. “The laser diode application at Fuji Xerox will demonstrate our ability to perform wafer-level burn-in successfully for very high contact density and high power density applications.”

VCSELs are used in high-speed, local-area data communications and represent the latest technology in semiconductor laser diodes. VCSELs are different from previous laser diodes in that, with the appropriate equipment, the light emitted from VCSELs can be tested while still in wafer form. Previous technologies required additional packaging steps before the laser diodes could be fully tested. The company’s FOX system allows test and burn-in at the wafer level, thereby avoiding the cost of packaging if the laser fails.

“The FOX system delivered to Fuji Xerox included our WaferPak™ cartridge, which utilizes one of our advanced interconnect technologies for contacting 6,000 VCSELs simultaneously on a single wafer,” said Carl Buck, vice president of marketing of Aehr Test Systems. “The modular nature of our WaferPak design allows us to match the best wafer contactor and signal distribution technologies for each customer’s specific application.”

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing DRAM and logic integrated circuits and has an installed base of more than 2,000 systems worldwide. Aehr Test has developed and introduced several innovative products, including the FOX, MTX, MAX3 and MAX4 systems, and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously.

The MAX system can effectively burn-in and functionally test complex devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand for Aehr Test's products and performance of the FOX system. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by Fuji Xerox of the FOX system for burning-in laser diodes, acceptance by customers of the FOX and WaferPak technologies, market acceptance of new products and the ability of new products to meet customer needs or perform as described, which could adversely affect demand for Aehr Test's products in calendar year 2004. See Aehr Test's recent 10-K and 10-Q reports filed with the SEC for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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